

Search Notes**Application/Control No.**

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Examiner

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Applicant(s)/Patent under Reexamination

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Art Unit

2625

SEARCHED

Class	Subclass	Date	Examiner
382	162, 176	4/26/2007	TDL
358	504, 518	4/26/2007	TDL
358	520	4/26/2007	TDL
updated		12/10/2007	TDL
358	1.9	12/10/2007	TDL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search History Printout	4/26/2007	TDL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Interference Search Printout		12/10/2007	TDL